Supplementary information

Chemical manipulation of phase stability and electronic behavior in Cu_{4-x}Ag_xSe_2

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Figure S1 Profile fitting of CuAgSe using Orthorhombic CuAgSe (S.G. P mmn).
Figure S2 Temperature-dependent X-ray diffraction of the high-temperature platinum holder. Peaks marked by an asterisk (*) belong to the platinum holder, where other peaks are unidentified, but a part of the holder background.
**Figure S3** Profile fitting of Cu$_3$AgSe$_2$ using Orthorhombic CuAgSe (S.G. Fm-3m).
Figure S4 Profile fitting of CuAgSe using cubic CuAgSe (S.G. Fm-3m).
Figure S5 Profile fitting of CuAg$_3$Se$_2$ using cubic CuAgSe (S.G. Fm-3m) and cubic Ag$_2$Se (S.G. Im-3m)